

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
10767182		PILLAI ET AL.
	<b>Examiner</b> Hoang, Hieu T	<b>Art Unit</b> 2452

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	217, 219	11/26/2007	HH
709	242, 249, 250	9/20/2011	HH
718	108	9/20/2011	HH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US PAT, US PGPUB)	11/26/2007	HH
NPL (Google, IETF, IEEE)	11/26/2007	HH
EAST (US PAT, US PGPUB)	9/8/2009	HH
EAST (US PAT, US PGPUB)	1/13/2010	HH
EAST (US PAT, US PGPUB)	5/9/2010	HH
EAST (US PAT, US PGPUB)	10/5/2010	HH
EAST (US PAT, US PGPUB)	5/25/2011	HH
EAST (US PAT, US PGPUB)	9/20/2011	HH
PLUS	9/20/2011	HH
Double patenting	9/20/2011	HH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
Interference search in EAST		9/20/2011	HH

/HIEU HOANG/  
Primary Examiner. Art Unit 2452